

<b>Notice of References Cited</b>	Application/Control No. 10/535,452		Applicant(s)/Patent Under Reexamination OGAWA ET AL.	
	Examiner Duy-Vu N. Deo		Art Unit 1792	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2004/0166376	08-2004	Kirino et al.	428/694.0TM
*	C	US-6,730,421	05-2004	Kirino et al.	428/831.2
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	K	US-			
	L	US-			
	M	US-			

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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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